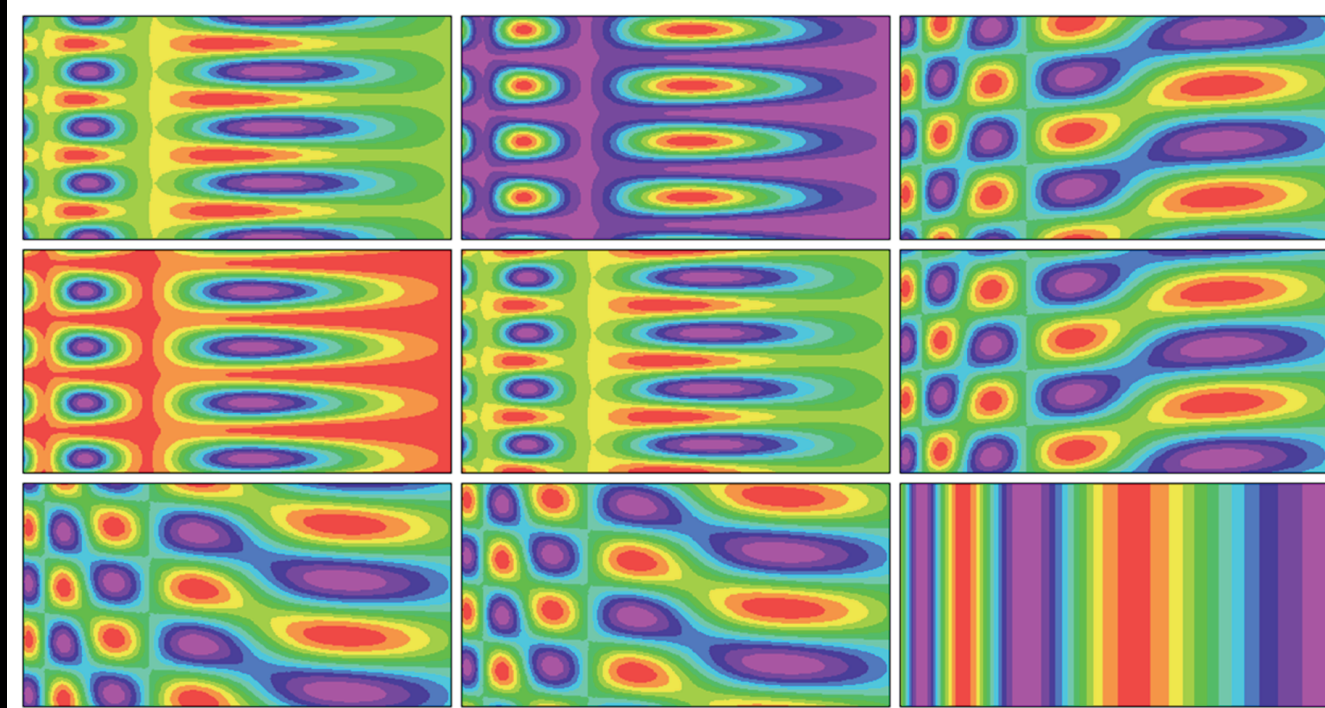


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COVER IMAGE Rotational MMSE data in transmission at normal incidence for a twisted linear retarder (showing only the “retarder” section of the MM). The wavelength range is 300 to 1000 nm. For more information see article “Mueller matrix spectroscopic ellipsometry” by James N. Hilfiker, Nina Hong and Stefan Schoeche on page 59, Issue 3-4, 2022.



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